

Schedule:

- 9:30 h **Welcome to Berlin**
- 9:40 h Nanometrology by optical means: an overview on coherent Fourier scatterometry and its future developments
Omar El Gawhary, VSL The Netherlands
- 10:05 h Characterization of two dimensional gratings by spectroscopic ellipsometry
Sven Peters, Adrian Blümich, SENTECH Instruments GmbH Germany
- 10:30 h New Trends in Spectroscopic Imaging Ellipsometry
Sebastian Funke, Accurion GmbH Germany
- 10:55 h How to make accurate scatterometry and ellipsometry measurement
Poul-Erik Hansen, DFM Denmark
- 11:20 h **coffee break**
- 11:45 h Combining time-resolved X-ray analysis and optical spectroscopy: Insights into the evolution of structure-property relations during film growth
Roland Mainz, HZB Germany
- 12:10 h Advanced characterization of thin-layered energy materials by X-ray spectrometry
Cornelia Streeck, PTB Germany
- 12:35 h Interface characterization of ultra-thin multilayer systems by combined analysis of diffuse scattering, reflectivity and fluorescence measurements
Anton Haase, PTB Germany

- 13:00 h **lunch break**
- 14:30 h Optical measurements of surface recombination in ALD coated nanostructures for photovoltaic applications
Hele Savin, Aalto University Finland
- 14:55 h Measurement of Physical Properties on Thin Film Materials
Heinz Renner, Linseis Messgeräte GmbH, Germany
- 15:20 h Functional mapping/imaging of multilayer organic solar cells
Fernando Castro, NPL UK
- 15:45 h Synchrotron-radiation-based ellipsometry in the visible to vacuum ultraviolet spectral range
Maciej Neumann, ISAS Germany
- 16:10 h **poster session / LabTour networking reception / bilateral stakeholder meetings**

Oral presentations are 20 minutes; 5 minutes are reserved for questions and answers. All contributors are asked to respect the time limit.

Registration

Participants are welcome to present their own related topics during the poster session.

Please register by 10th of January 2016 at:

<http://www.ptb.de/emrp/2597.html>

Participants are expected to finance their own travel and accommodation expenses.



Organizing Committee

Dana Maria Rosu, BAM
Michael Kolbe, PTB
Andreas Hertwig, BAM
Cornelia Streeck, PTB

Contact

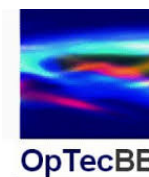
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We would like to thank the European X-ray Spectrometry Association for their support.



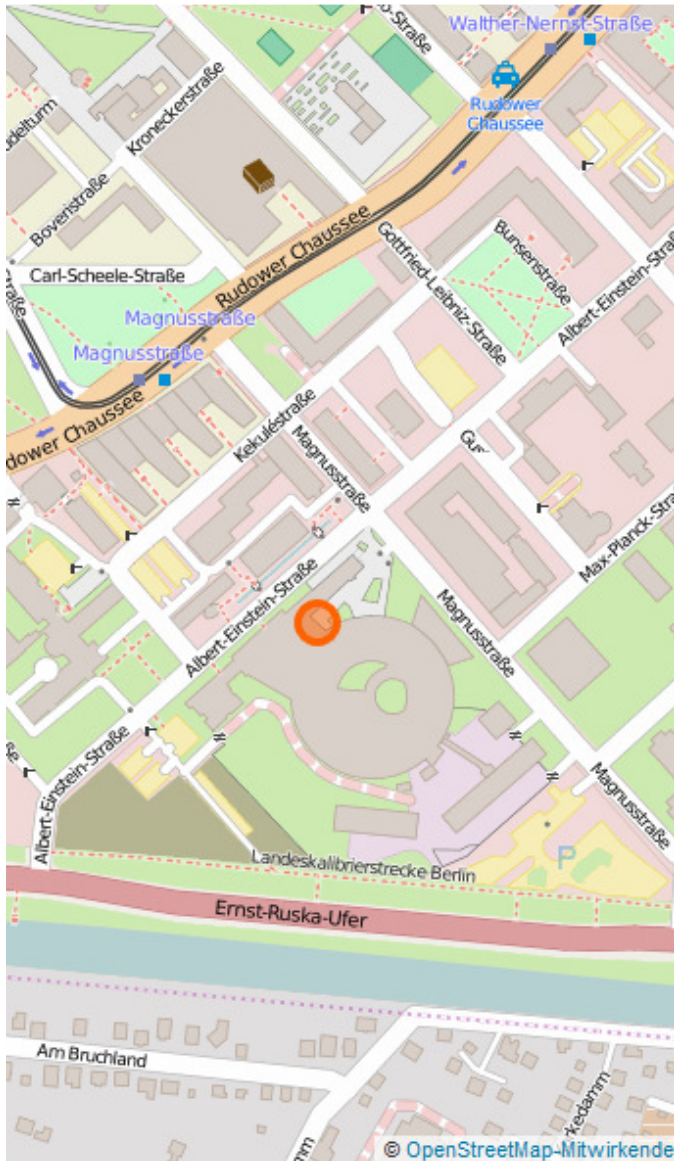
In cooperation with the Berlin-Brandenburg Photonics Cluster



Venue

Helmholtz-Zentrum Berlin / BESSY II

lecture hall
Albert-Einstein-Str. 15
12489 Berlin-Adlershof
Germany



Access to venue in Berlin-Adlershof

In Adlershof, the venue can be reached from S-Bahnhof Adlershof (suburban railway (S-Bahn) station Adlershof) by a 15-minute walk or two stations with bus or tram. The BESSY II Building is at Albert-Einstein-Str. 15.

With Public Transport:

From S-Bahn station Adlershof
Bus 162, 164 or Tram 60, 61 stop: Magnusstraße

From Berlin-Schönefeld Airport:

S-Bahn line S 9 or S 45 to S-Bahn station Adlershof (about 10 min.) see above

From Berlin-Tegel Airport:

Bus TXL to S-Bahn station Beusselstraße or bus 109 to suburban railway station Jungfernheide;
from here: S-Bahn line S 42 to Neukölln, then transfer (same platform) to S45 or S 46 to Adlershof
or S-Bahn line S 41 to Treptower Park, transfer here to S 8 or S 9 to Adlershof (about 1 h)

From Berlin Central Railway Station ("Hauptbahnhof"):

S-Bahn line S 3, S 5, S 7 or S 75 to Ostkreuz, from Ostkreuz
S-Bahn line S 8 or S 9 to Adlershof (about 30 min)

From Berlin Südkreuz Railway Station:

S-Bahn line S 45 or S 46 to Adlershof (about 20 min.)

For JRP members attending the partners meeting at BAM we will try to organize a shuttle service.

Accommodation in Berlin-Adlershof

There are three hotels nearby the venue:

<http://hotel-berlin-adlershof.dorint.com/>

<http://www.airporthotel-berlin-adlershof.de/>

<http://www.adaptberlin.de>



Workshop on advanced optical measurements

January 27th, 2016

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